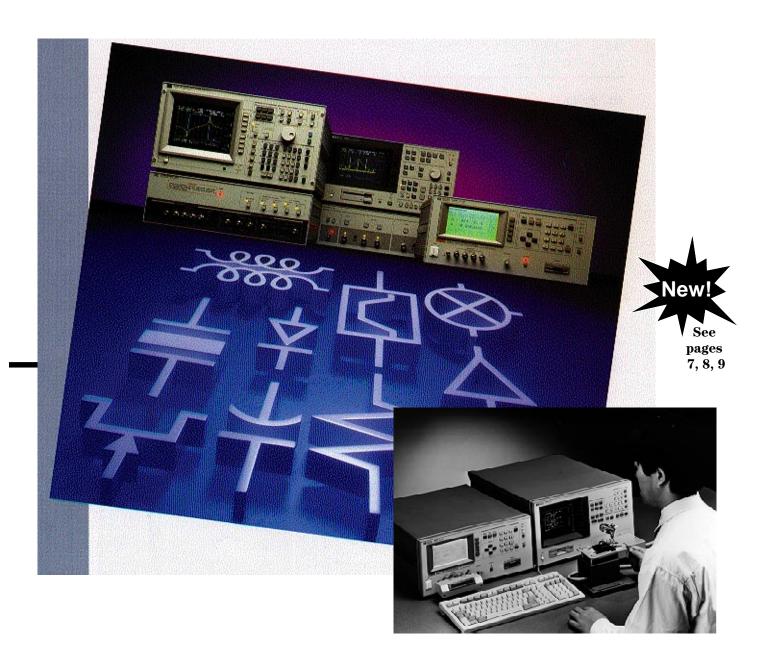


LCR Meters, Impedance Analyzers, and Test Fixtures Selection Guide

Component and Material Measurement Solutions



Cost Effective Solutions for Your Applications

Whether your application is in R&D, production, quality assurance, or incoming inspection, HP has the right impedance measurement solution for you. HP has a complete line of impedance test equipment and test accessories to help you task efficiently. When you choose an impedance measurement product from HP, you get more than accurate and reliable test results. HP offers:

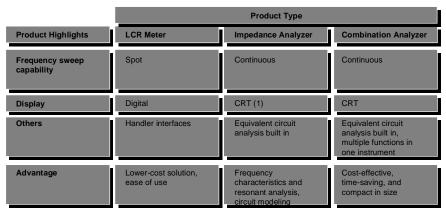
Complete solution: Covering frequencies from 5 Hz to 1.8 GHz, HP's impedance product line offers your the widest selection of equipment for your application. In addition, several third-party companies have complementary products designed to work with HP equipment for special applications. This brochure gives an overview of all the products you can choose from.

Knowledge: HP has decades of experience providing impedance measurement solutions. Years of experience and continuing technical innovations go into the design and manufacturing of each HP LCR meter and impedance analyzer. HP also has a list of technical publication to assist you in many different applications (see page 14 for full listing.)

Convenience : Any time you have an impedance measurement need, help is only one phone call away. Calling HP will put you in contact with one of our trained engineers to help you find a solution.

Selecting the Best solution

HP's offers three types of impedance measurement solutions:



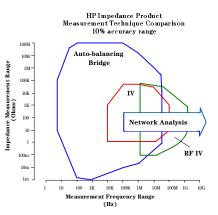
(1) Except HP 4192A, which has an LCD display and no equivalent circuit analysis function

Advanced Measurement Techniques for a Wide Range of Applications

Figure 1 is a comparison of different measurement techniques used in HP's LCR meter and impedance analyzers. As you can see, each technique has special measurement advantages:

- Auto-balancing bridge offers widest impedance measurement range with typical frequency range with typical frequency range of 5 Hz to 40 MHz. This technique is best for low-frequency, general-purpose testing.
- IV technique covers from 10 kHz to 100 MHz with a more focused impedance measurement range. IV technique also allows probing for in-circuit testing.
- Network analysis offers the highest frequency coverage, but works best when the measurement range is close to 50 ohms. With this measurement technique, impedance values are derived from reflection coefficients. Network analysis is most widely used for RF and microwave component and circuit analysis.

• RF IV, an enhancement of the IV technique, offers some of the high-frequency benefit of network analysis while retaining some of the impedance measurement range of the IV technique. Designed for accuracy and high-frequency performance, the RF IV technique is excellent for RF component analysis, especially for small inductance and capacitance values.



How to Use This Selection Guide

Table 1 is a summary of all of HP's impedance products. It is designed to assist you in better comparing HP's wide range of instrumentation and in choosing possible solutions for your applications, depending on your requirements in the following areas:

- Test frequency range.
- Device type or application type.
- Accuracy requirement.
- Any other special needs.

If you find several possible solutions for your application, go to the corresponding pages to find more details about each product. Call HP if you need further assistance.

| Special Features | A,B | A,B | A,B | U | A,B | A,B | ۵ | | ш | | | | ٥ | ۵ | | ۵ |
|---|------------------------------|-----------------------|-----------------------|---|-------------------|------------------------------|---------------------------|--------------------------|------------|----------------------|--------------|------------------------------------|----------------------------|------------------------|-----------------------------|-----------------------------|
| Z Measurement Range (ohms) | 0.1 to 50k | 0.03 to 30k | 2 to 5k | 0.1m to 1M | 0.01 to 100M | 0.1 to 1M | 0.01m to 99.9999 | 0.01m to 99.9999 | 200m to 3k | 0.001p to $200\mu^4$ | 1m to 100M | 200m t o10k | Q: 5 to 1000 | 10μ to $100k$ | 10k to 1.6x10 ¹⁶ | 10k to 1.0x10 ¹⁵ |
| Basic Z Accuracy(%)3 | 0.8 | 1.5 | m | 0.1 | 0.17 | 1.5 | 0.05 | 0.1 | 1.0 | 0.05 | 0.1 | e | 2 | 0.4 | 0.6 | ~ |
| Frequency Range (Hz) Device Type/Applications | 1M to 1.8G | 100k to 500M | 100k to 1.8G | 5 to 13M | 100 to 40M | 10k to 100M | 20 to 1M | 75k to 30M | 1M to 1G | 1k & 1M only | 1100 to 100k | 1M to 180M | 75k to 30M | 1k only | HP 4339B=dc only | HP 4349B=dc only |
| Amplifier Amplifier Antenna Battery Cable apacitance High Accuracy Capacitor, Freq. Analysis Circuit Design Circuit Design Circuit Packaging Inductor, Fower, LF Inductor, Fower, LF Inductor, FRF LCD Material Liquid Materials Magnetic Head Optical Isolator Power Supply Read Channel (Disk Drive) Resistor Resonator, Ceramic Semiconductor, C-V miconductor, Input/Output Solenoid solucer, Sonar & Pressure Transformer, LF & Power | •• * •** * * •*• ••••• | x | ** * ** * * ** *** | ••••• | ●●★★ ★★★●●●●★★★★★ | <u> </u> | • *•* *•• •* *** *• •* *• | •••• × • •*****••• * *•• | • • * | * | * • • • * | • * • • • * • • • * • | * ** | * * • • | * • * * | |
| Transistor, FET Transistor, Bipolar ອາ | 4 | • | • | • 5 | 4 | 4 | 6 | • | ~ | თ | ∞ | ~ | ٥ | 7 | œ | |
| HP Solution | HP 4291A | HP 4195A ¹ | HP 4396A ² | HP 4192A | HP 4194A | HP 4194A with HP 41941A/B | HP 4284A | HP 4285A | HP 4286A | HP 4278A | HP 4263B | HP E4196A with Opt. 001 and 010 | HP 4285A with HP 42851A | HP 4338B | HP 4339B/HP 4349B | |
| Product Family Type of Measurement | HF/RF Impedance Analyzers | Network/Spectrum/ | Impedance | Impedance Impedance and Analyzers Gain-Phase | | | LCR Precision Meters | | | High Speed/Precision | Low Cost | | Precision Q | Resistance: Milliohm H | - High Resistance | |

Product Highlights: Impedance Analyzers

measurement accuracy and sophisticated measurement functions:

- Frequency sweep capability lets you customize where and how test data will be takes.
- Impedance analyzers provide high Built-in equivalent-circuit analysis Advanced calibration and computes a multi-element circuit model of the device-under-test.
 - Color CRT can display multiple sets of measurement curves at the same time.
- compensation methods reduce measurement errors.





HP 4291A 1.8 GHz Impedance/Material Analyzer

- Provides top-of-the-line solution for measuring impedance from 1 MHz to 1.8 GHz, with an optional material-test function for measuring permitivity and permeability.
- Ideal instrument for RF Surfacemount inductors. capacitors, PC board materials. and magnetic toroids.
- Measurement parameters: |Z|, |Y|, Θ , R, X, G, B, C, L, R, D, Q.
- Material parameters : ε , ε' , ε'' , μ , μ' , μ"

HP 4194A Impedance/ **Gain-Phase Analyzer**

- Versatile instrument with 3 measurement capabilities: Impedance only: 100 Hz to 40 MHz Impedance with HP 41941A/B impedance probe: 10 kHz to 100 MHz Gain/phase: 10 MHz to 100 MHz
- Great R/D tool for all types of component and circuit analysis.
- Measurement parameters: |Z|, |Y|, Θ, R, X, G, B, Ĉ, L, R, D, Q.

Product Highlights: Network/Spectrum/Impedance Analyzers

These combination analyzers offer a cost-effective and time-saving alternative. Instead of buying a rack full of stand-alone test equipment and spending extra time to make them work together, you can get a combination analyzer that has all the functions you need and is ready to go when you press the power-on button. For impedance analyzers have the same advanced features as the impedance analyzers described on page 4.



1414 Cit and con

HP 4396A Network/Spectrum/ Impedance Analyzer (with HP 43961A RF Impedance Test Kit and HP 4396A opt.010)

- 1.8 GHz three-in-one analyzer with no sacrifice in performance.
- Advanced features for meeting your future test requirements: gated spectrum analysis for pulsed signal analysis, digital resolution bandwidth for faster sweeps, and more.
- Saves you money and time for RF component and circuit analysis.
- Measurement parameters: |Z|, |Y|, Θ , R, X, G, B, C, L, R, D, Q.

HP 4195A Network/Spectrum/ Impedance Analyzer (with HP 41951A Impedance Test Set)

- Most popular combination analyzer for components and circuit design from 5 Hz to 500 MHz
- Three functions for a complete analog measurement system.
- Best-valued bench-top tool for R&D.
- Measurement parameters: |Z|, |Y|, Θ , R, X, G, B, C, L, R, D, Q.

1. 1.

0

U

ÖÖÖ

000

000

000

000

Ö

....

Ö

 $\overline{\mathbf{O}}$

0 0 0 0

0000

õ

0

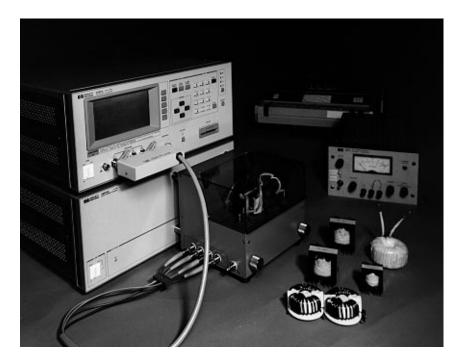
Product Highlights: Precision LCR Meters

Designed for measurement precision and ease-of-use, this family of LCR meters fits both R&D and production applications. Although the LCR meters do not have all the sophisticated features as impedance analyzers, the LCR meters offers excellent performance at an affordable price:

- Wide selection of frequency range from 20 Hz to 1 GHz.
- Frequency list sweep for continuos testing at multiple frequency points.
- Great for general-purpose testing of leaded components surface-mount components, materials, and more.
- HP-IB and handler interface for easy test automation in production environment.

HP 4284A Precision LCR Meter

- 0.05% basic accuracy.
- 20 Hz to 1 MHz
- Option 001 adds ± 40V internal dc bias voltage
- For testing power inductors and transformers, choose option 002, HP 42841A, and HP 42841A/B to get up to 20 A dc bias current.¹
- Measurement parameters: |Z|, |Y|, Θ , R, X, G, B, C, L, R, D, Q, ESR





HP 4285A Precision LCR Meter

- 0.1% basic accuracy
- 75 kHz to 30 MHz
- Option 001 adds ± 40V dc bias voltage.
- Option 002, HP 42841A, and HP 42842C provide up to 10 A dc bias current.
- Measurement parameters: |Z|, |Y|, Θ , R, X, G, B, C, L, R, D, Q, ESR.
- Best Q measurement solution up to 30 MHz when used with option 002 and HP 42851A Precision Q Adapter.

Product Highlights: Precision RF LCR Meter



HP 4286A RF LCR Meter

- 1.0% basic accuracy and wide impedance range
- Reliable Q measurement (6% @Q=100, 100MHz)
- 1 MHz to 1 GHz frequency range
- Measurement time fo 15 msec
- Handler and HP-IB Interfaces
- 1m/3m selectable extension cable with small APC3.5 test head
- SMD fixtures
- Measuremet parameters: |Z|, |Y|, θ , R, X, G, B, C, L, R, D, Q

Product Highlights: Basic Products

The following products are designed for basic or specialpurpose applications. Their features are optimized to achieve maximum performance for the particular applications.



HP 4338B Milliohmmeter $(1m\Omega \text{ to } 100k\Omega)$

- 1 kHz ac measurement with selectable test signal current from 1 mA to 10 mA.
- Designed for utra-low resistance measurements of switches, batteries, relays, cables, connectors, and PC boards.
- Measurement parameters: R, X, |Z|, L, θ .
- Contact check function for reliable tests.
- Select the number of displayed digits (3, 4, or 5).

HP 4263B LCR Meter



- Spot frequency testing at 100 Hz, 120 Hz, 1 kHz, 10 kHz, and 100 kHz. (optional 20 kHz)
- Compact, easy-to-use, entry-level LCR Meter.
- Measurement Parameters: |Z|, |Y|, θ, R, X, G, B, C, L, R, D, Q, ESR.
- Add N, M, DCR (Option 001) for transformer/Coil measurements.
- Set signal level (20 mV to 1 Vrms) in 5 mVrms steps.
- Monitor actual ac voltage and current levels.
- Contact check function for reliable tests.
- Select the number of displayed digits (3, 4, or 5).

HP E4916A Crystal Impedance / LCR Meter (with Opt. 001 and 010)



- Spot frequency testing from 1 MHz to 180 MHz.
- Compact, easy to use, entry-level RF LCR meter.
- 3.0% basic accuracy.
- Floating or grounded measurement.
- Measurement parameters: |Ζ|,|Y|,θ,R,X,G,B,C,L,R,D,Q.
- Special function for crystal resonator testing.

HP 4339B High-Resistance Meter



- Test voltage: 0.1 to 1000 Vdc.
- Measurement range: R: 1 x 10³ Ω to 1.6 x 10¹⁶ Ω, I: 60 fA to 100 μA.
- Great solution for evaluating leakage current and insulation resistance of components.
- Can be programmed to measure surface and volume resistivity.
- Measurement parameters: I, R, volume and surface resistivity.
- Contact check function for reliable tests.
- Select the number of displayed digits (3, 4, or 5).

Product Highlights: Special Interest Products

HP 4349B 4-channel High-Resistance Meter

- Four-channel simultaneous testing.¹
- Fast contact check function for reliable testing.
- Measurement range: R: 1 x $10^3 \Omega$ to 1.0 x $10^{15} \Omega$, I: 3 pA to 100 μ A

1. HP 4349B, because it has 4-measurement channels, has no internal dc source so an external dc source must be required.



HP 4192A LF Impedance Analyzer

- Unique 5 Hz-to-13 MHz frequency range for component test or circuit design evaluation.
- Only 4-terminal instrument that can make grounded or floating measurement.
- Measurement parameters: |Z|, |Y|, Θ , R, X, G, B, C, L, R, D, Q.
- Floating or grounded measurements.

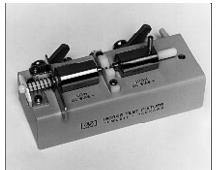


HP 4278A Capacitance Meter

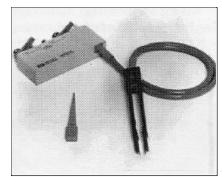
- Two standard frequencies (1 kHz and 1 MHz) for capacitor testing.
- Measurement speed and accuracy optimized for production testing
- Measurement parameters : C, D, Q, ESR, G.



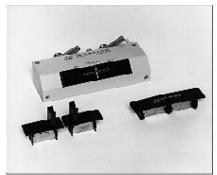
Components



HP 16034E SMD/Chip Test Fixtures Frequency: <= 40 MHz Maximum dc bias: ± 40V



HP 16334A SMD/Chip Tweezers Frequency: <= 15 MHz Maximum dc bias: ± 42V



 HP 16047A/D Axial & Radial Test

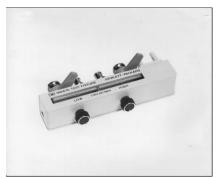
 Fixture

 Frequency:
 A: <=13 MHz,</td>

 D: <= 40 MHz</td>

 Maximum dc bias:
 A: ± 35 V,

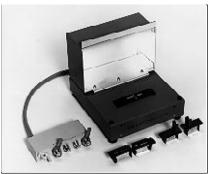
 D: ± 40 V



HP 160 47C High Frequency Test Fixture Frequency: <= 40 MHz Maximum dc bias: ± 35V



HP 16047B Axial and Radial Test Fixture with Safety Cover Frequency: <= 2 MHz Maximum dc bias supplied from instrument: ± 35V



HP 16005A Axial and Radial Test Fixture with Safety Cover Frequency: <= 2 MHz Maximum externally supplied dc bias: ± 200V

Test Leads and Clips



HP 16048A/D/E BNC Test Leads Frequency: A: <= 30 MHz, D: <= 30 MHz, E: <= 1 MHz Cable length: A: 0.94m, D: 1.89m, E: 3.8m Maximum dc bias: ± 300V

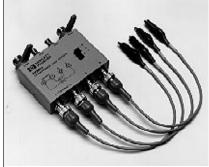


HP 16048B SMC Test Leads Frequency: <= 30 MHz Cable length: 0.94m Maximum dc bias: ± 300V



HP 16089A/B/C/D Clip Leads Connector type: A/B/C: Kelvin, D: Alligator Frequency: 5 Hz to 100 kHz Cable length: A/B/C: 0.94 m, D: 1.3m

Others



HP 16060A Transformer Test Fixture Frequency: dc to 100 kHz Use with only HP 4263B



HP 16064A LED Display/Trigger Box For production test applications.



HP 16065C External Bias Adapter Frequency: 100 Hz to 1 MHz Maximum externally supplied dc bias: $\pm 40 \text{ V}$

Balanced/Unbalanced Test Fixture



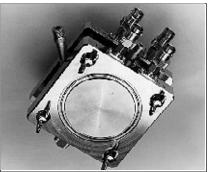
HP 16314A Balanced/Unbalanced **4-Terminal Converter** Frequency: 100 Hz to 10 MHz Connectors: 4 BNCs (unbal.), 2 signal terminals & 1 ground terminal (bal.) Characteristic Z: 50 ohms

Material Measurements

Both are recommended for use with HP 4284A & HP 4285A LCR Meters and HP 4194A Impedance Analyzer.

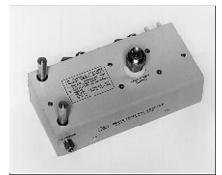


HP 16451B Dielectric Test Fixture **Measurement parameters:** Capacitance (C), and dissipation factor (D) Material-under-test size: thickness: <=10 mm. diameter: 10 to 56 mm Frequency: <= 30 MHz



HP 16452A Liquid Test Fixture Measurement parameter: impedance, dielectric constant (er) Liquid sample quantity: <=6.8 ml Frequency: <= 20 Hz to 30 MHz

RF Adapters



HP 16085B Four-terminal-pair to APC7 Adapter Frequency: <= 40 MHz Maximum dc bias: ± 40V

Balanced/Unbalanced Test Fixtures



HP 16315A 50 ohm Balanced/50 ohm **Unbalanced Converter** Frequency: 100 Hz to 10 MHz HP 16316A 100-ohm Balanced/50-ohm **Unbalanced Converter** Frequency: 100 Hz to 10 MHz HP 16317A 600-ohm Balanced/ 50-ohm **Unbalanced Converter** Frequency: 100 Hz to 3 MHz

All have 1 BNC connector (unbalanced) and 2 signal terminals and 1 ground terminal (balanced).

RF SMD/Chip Components



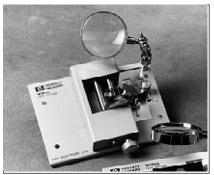
HP 16092A Axial, Radial, and SMD Test Fixture Frequency: <= 500 MHz Maximum dc bias: ± 40 V



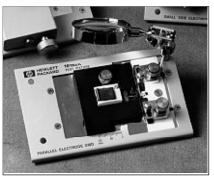
HP 16093A Two-terminal Binding Post Test Fixture Frequency: <= 250 MHz Maximum dc bias: ± 40V



HP 16093B Three-terminal Binding Post Test Fixture Frequency: <= 125 MHz Maximum dc bias: ± 40 V



HP 16191A Side-Electrode SMD Test Fixture Frequency: dc to 2 GHz Maximum dc bias: ± 40 V



HP 16192A Parallel-Electrode SMD Test Fixture Frequency: dc to 2 GHz Maximum dc bias: ± 40 V



HP 16193A Small Side-Electrode SMD Test Fixture Frequency: dc to 2 GHz Maximum dc bias: ± 40V



HP 16200A External DC Bias Adapter *Freequency:* 1 MHz to 1 GHz *External dc bias:* Up to 5A, ± 40 V

Material Measurements



HP 16453A Dielectric Test Fixture Frequency: 1 MHz to 1.8 GHz Sample size (smooth sheets only): thickness: <=3 mm, diameter: >= 15 mm



HP 16454A Magnetic Test Fixtures Frequency: 1 MHz to 1.8 GHz Sample size (toroids only) : height: <=10 mm, inner diameter: >=3.1 mm, outer diameter: <=20 mm

Simplify and Improve Your Measurements With HP Test Accessories

Selecting a test fixture is as important as selecting the right instrument. HP offers a wide range of accessories for axial. radial and SMD/Chip devices. In addition, a variety of test leads are available to simplify remote testing and systems applications. External test fixtures with safety covers are also available.

You will improve your measurement results with the proper test fixture.

- Move reliable and repeatable measurement
- Higher through-put
- Fewer handling errors
- Tighter test limits
- Better measurement accuracy

For sales information or technical assistance call Hewlett-Packard.

| | | HP 4192A | HP 4194A | HP 4194A with HP 41941A/B | HP4195A with HP 41951A | HP 4263B | HP 4278A | HP 4284A | HP 4285A | HP 4286A | HP 4291A | HP 4396A with opt. 010 and HP 43961A | HP E4916A with Opt.001 and 010 |
|----------------|--|----------|--------------|------------------------------|---------------------------|----------|-----------------------------|---------------------------|---------------|---------------------------|----------|---|-----------------------------------|
| HP 16034E | SMD/Chip Test Fixtures | | | | | | | | | | | | |
| HP 16047A | Axial and Radial | | | | | | | | | | | | |
| HP 16047B | Axial and Radial with Safety Cover | | | | | | | | | | | | |
| HP 16047C | HF Axial and Radial | | | | | | | | | | | | |
| HP 16047D | Axial and Radial | | | | | | | | | | | | |
| HP 16048A | One Meter Test Leads, BNC | | | | | | | | | | | | |
| HP 16048B | One Meter Test Leads, SMC | | | | | | | | | | | | |
| HP 16048D | Two Meter Test Leads, BNC | | | | | | | | | | | | |
| HP 16048E | Four Meter Test Leads, BNC | | | | | | | | | | | | |
| HP 16060A | Transformer Test Fixture | | | | | | | | | | | | |
| HP 16065A | Ext. Voltage Bias with Safety Cover | | | | | | | | | | | | |
| HP 16065C | External Bias Adapter (<=40 vdc) | | | | | | | | | | | | |
| HP 16085B | Four-Terminal Pair to APC-7 Adapter | | | | | | | | | | | | |
| HP 16089A/B/C/ | DClip Leads | | | | | | | | | | | | |
| HP 16092A | RF Spring Clip: Axial, Radial and SMD | •1 | •1 | ●2 | | | | 1 | 1 | 1 | | | ●2 |
| HP 16093A | RF Two Terminal Binding Post | • 1 | • 1 | •2 | | • | | 1 🔵 | 1 | 1 | | | • ² |
| HP 16093B | RF Three Terminal Binding Post | • 1 | • 1 | •2 | | | | 1 | 1 | 1 | | | • ² |
| HP 16094A | RF Probe Tip/Adapter | •1, | 3 1 , | ³ • ³ | •3 | | ³ • ¹ | , 3 • ¹ | ,3 ● 1 | , 3 ● [€] | | ³ • ³ | |
| HP 16095A | LF Probe Adapter | | | | | | | | | | | | |
| HP 16099A | RF Probe to APC-7 Adapter | | | | | | | | | | | | \bullet^2 |
| HP 16191A | Side-Electrode SMD Test Fixture | •1 | •1 | •2 | | •1 | • 1 | | | 1 | | | • ² |
| HP 16192A | Parallel Electrode SMD Test Fixture | •1 | •1 | •2 | | •1 | • | 1 🛛 1 | | 1 | | | • ² |
| HP 16193A | Small Side Electrode SMD Test Fixture | • 1 | • 1 | •2 | | •1 | | 1 | | 1 | | | • ² |
| HP 16194A | High Temperature Component | _1 | _1 | 2 | | _1 | | | | 1 | | | 2 |
| | Test Fixture, SMD and Leaded | | | | | | | | | | | | |
| HP 16200A | External DC Bias Adapter | | | | | | | | | | | | |
| HP 16314A | 4-Terminal Balun | | | | | | | | | | | | |
| HP 16315/6/7A | BNC Balun/Binding Post Balun | | | | | | | | | | | | |
| HP 16334A | SMD/Chip Tweezer | | | | | | | | | | | | |
| HP 42842A/B | High Bias Current 20A/40A Test Fixture | | | | | | | • | 1 | | | | |
| HP 42842C | High Bias current 10A Test Fixture | | | | | | | | • | | | | |
| HP 16451A | Dielectric Material Test Fixture | | | | | | | | | | | | |
| HP 16452A | Liquid Test Fixture | | | | | | | | | | | | |
| HP 16453A | Dielectric Test Fixture | | | | | | | | | | | | |
| HP 16454A | Magnetic Test Fixture | | | | | | | | | | | | |

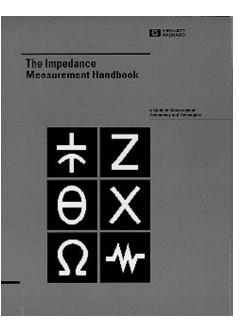
Note: Refer to the accessory descriptions for frequency and operational limits. 1 Compatible when used in conjunction with HP 16085B. 2 Compatible when used in conjunction with HP 16099A. 3 APC-7 to APC-7 cable is required. 4.See page 6 for configuration details 5.Do not connect the ground lead to the instrument. 6 APC-3.5 to APC-7 Adapter is required.

Applications Information

Helping You Make Better Measurements

HP's application knowledge can help you make better measurements. Use the matrix below to select the HP Application Notes of interest. For copies of these Application Notes, contact your local HP sales office

| App Note | Title/Subject | Featured | HP Pub# |
|------------|--|---------------|------------|
| 1210-1 | Package & component meas. | HP 4194A, ICM | 5091-1799E |
| 380-2 | Measuring cable parameters | HP 4284/5A | 5950-2399 |
| 369-10 | High accuracy & fast RF inductor testing | HP 4285A | 5091-1596E |
| 369-8 | DC current-biased inductance meas. | HP 4284A, | 5950-2367 |
| 369-7 | Cap meas. of liquid crystal cells | HP 4284A | 5950-2994 |
| 369-6 | Impedance testing using scanners | HP 4284A | 5950-2975 |
| 369-5 | Multi-frequency C-V meas. of semiconductor | HP 4284A | 5950-2953 |
| 369-4 | Incoming inspection | HP 4284A | 5950-2952 |
| 369-3 | Impedance meas. of magnetic head | HP 4284A | 5950-2951 |
| 369-1 | Component & material impedance meas. | HP 4284A | 5950-2949 |
| 357-4 | Testing magnetic disk read circuit | HP 4195A | 5950-2398 |
| 357-3 | Filter evaluation & limit testing | HP 4195A | 5950-2933 |
| 357-2 | S-parameter & distortion meas. of amplifier | HP 4195A | 5950-2932 |
| 357-1 | Evaluation of IF circuits | HP 4195A | 5950-2931 |
| 346-3 | Impedance meas. using open/short/load comp. | General | 5091-6553E |
| 346-2 | Balance circuit meas. | General | 5091-4480E |
| 346 | Designing external dc bias circuit | General | 5950-2912 |
| 339-14 | Testing switching power supplies | HP 4194A | 5950-2977 |
| 339-13 | Solid mat'l dielectric constant meas. | HP 4194A | 5950-2935 |
| 339-12 | HP-IB programming hints | HP 4194A | 5950-2929 |
| 339-11 | Filter testing for production | HP 4194A | 5952-7887 |
| 339-9 | Negative impedance meas. of crystal osc. | HP 4194A | 5950-2924 |
| 339-8 | Constant current meas. | HP 4194A | 5950-2923 |
| 339-7 | Evaluation of LISN & voltage probes for EMI | HP 4194A | 5950-2922 |
| 339-6 | Static head testing for disk drives | HP 4194A | 5952-7871 |
| 339-5 | Multi-frequency C-V meas. for semiconductor | HP 4194A | 5950-2919 |
| 339-4 | Characteristic impedance of balanced cables | HP 4194A | 5952-2918 |
| 339-3 | Crosstalk & impedance meas. of PCB patterns | HP 4194A | 5952-7863 |
| 339-2 | Characteristic impedance of PCB | HP 4194A | 5950-2908 |
| 339-1 | Impedance char. of resonators | HP 4194A | 5950-2882 |
| 339 | Component & circuit evaluation | HP 4194A | 5950-2856 |
| 317 | Practical design & evaluation of hi-freq. circuits | HP 4193A | 5953-6910 |
| SN4291-1 | Chip capacitor testing | HP 4291A | 5091-9267E |
| SN4291-2 | Chip inductor testing | HP 4291A | 5091-9904E |
| SN4291-3 | Temperature coefficient testing for components | HP 4291A | 5962-6922E |
| SN4291-4 | Permitivity measurement | HP 4291A | 5962-6973E |
| SN4291-5 | Permeability measurement | HP 4291A | 5962-6972E |
| SN4291-6 | Electronic characterization of IC packages | HP 4291A | 5962-9725E |
| PN16451B-1 | Dielectric constant meas. using the HP 16451B | HP 16451B | 5962-9522E |
| | Impedance Meas. Handbook | General | 5950-3000 |



The Impedance Measurement Handbook is a comprehensive guide to impedance measurements. Beginning with the basics it contains in-depth practical advice to help you make better measurements. This 104-page handbook answers many commonly asked questions.

To get your copy, contact your local HP sales office.

Complementary Products and Accessories

To help you find a complete solution, we have listed the following companies that make complementary products or specialized accessories for HP's impedance measurement products. Please contact each company directly if you are interested in its products. (HP does not make any special endorsement of these companies' products; this list is for reference only.)

| Company Name | Product Specialty/Expertise | Address & Phone Number | | | |
|--|---|---|--|--|--|
| Cascade Microtech Inc. | Microwave frequency probes, probe stations, and accessories for semiconductor & IC applications. | 14255 SW Brigadoon Ct. Beaverton, OR 97005 (503) 626-8245 | | | |
| Innovative Measurement Solutions (IMS) | Software and consulting for material analysis. | P.O.Box 70546 Marietta, GA (404) 578-8695 | | | |
| Inter-continental Microwave | Standard and custom- designed RF and microwave test fixtures and calibration standards | 1515 Wyatt Drive Santa Clara, CA 95054 (408) 727-1596 | | | |
| Ismeca USA, Inc. | Standard and custom- designed assembly and automation equipment (e.g. handlers) for electronic manufacturing. | 2440 Impala Drive Carlsbad, CA 92008 (619) 931-1153 | | | |
| North Hills Electronics | Wide-band transformers (baluns) to 300 mHz for balanced measurement. | 575 Underhill Blvd. Syosset, NY 11791 (516) 682-7740 | | | |
| Palomar Systems | Standard and custom designed assembly and automation equipment (e.g. handlers) for electronic manufacturing. | 2310 Aldergrove Ave. Escondido, CA 92029 (619) 741-9717 | | | |
| Tabai Espec/ ESPEC Corp. (America) | Temperature chamber for component & material Testing. | 425 Gordon Inductrial Ct.SW Grand Rapids, MI 49509 (616) 878-0270, or 1-800-537-7320 | | | |



For more information on Hewlett-Packard Test and Measurement products, applications, or services please call your local Hewlett-Packard sales office. A current listing is available via the Web through AccessHP at http://www.hp.com. If you do not have access to the internet, please contact one of the HP centers listed below and they will direct you to your nearest HP representative.

United States:

Hewlett-Packard Company Test and Measurement Organization 5301 Stevens Creek Blvd. Bldg. 51L-SC Santa Clara, CA 95052-8059 1 800 452 4844

Canada:

Hewlett-Packard Canada Ltd. 5150 Spectrum Way Mississauga, Ontario L4W 5G1 (905) 206 4725

Europe:

Hewlett-Packard European Marketing Centre P.O. Box 999 1180 AZ Amstelveen The Netherlands

Japan:

Hewlett-Packard Japan Ltd. Measurement Assistance Center 9-1, Takakura-cho, Hachioji-shi, Tokyo 192, Japan Tel: (81) 426 48 3860 Fax: (81) 426 48 1073

Latin America:

Hewlett-Packard Latin American Region Headquarters 5200 Blue Lagoon Drive 9th Floor Miami, Florida 33126 U.S.A. (305) 267 4245/4220

Australia/New Zealand:

Hewlett-Packard Australia Ltd. 31-41 Joseph Street Blackburn, Victoria 3130 Australia 131 347 ext. 2902

Asia Pacific:

Hewlett-Packard Asia Pacific Ltd 17-21/F Shell Tower, Times Square, 1 Matheson Street, Causeway Bay, Hong Kong (852) 2599 7070

© Copyright 1996 Hewlett-Packard Company Data subject to change Printed in U.S.A. 5/96 5952-1430E